

HQ:NSC15/Pt

Conductive Tapping Mode AFM Probe

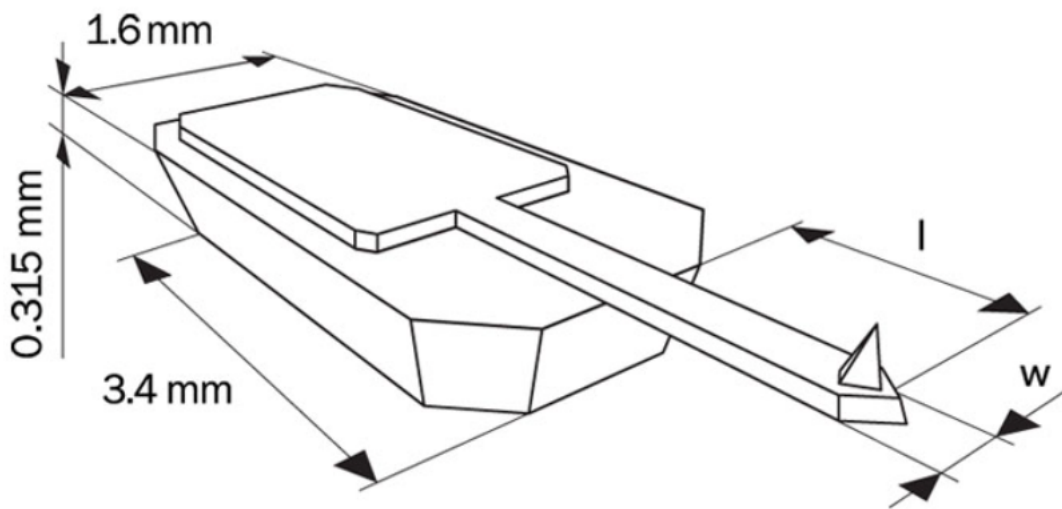
AFM probes of the HQ:NSC15 series are generally used in tapping mode for imaging hard samples when high topographic and phase contrast are necessary. These AFM probes are also suitable for non-contact mode.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

The overall 30 nm platinum coating is electrically conductive and chemically inert. It also enhances the laser reflectivity of the AFM cantilever. The resulting coated AFM tip radius is below 30 nm.

Coating

Electrically Conductive



AFM Probe Specifications

AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 μm (12 – 18 μm)*	40°	< 30 nm

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	40 N/m (20 – 80 N/m)*	325 kHz (265 – 410 kHz)*	125 μm (1 – 130 μm)*	30 μm (27 – 33 μm)*	4 μm (3.5 – 4.5 μm)*

* typical values